

<b>Notice of References Cited</b>	Application/Control No. 10/090,458	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Bork (Genome Research, 10:348-400, 2000)			
	V	Smith et al (Nature Biotechnology 15:1222-1223, 1997)			
	W	Brenner (TIG 15:132-133, 1999)			
	X	Broun et al. (Science 282:1315-1317, 1998)			

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	U	Van de Loo et al. (Proc. Natl. Acad. Sci. 92:6743-6747, 1995)
	V	Accession number BG149983, date entered 2/5/01.
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